

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Yoel ARIELI, et al.

Serial No.: 09/829,435

Group No.: 2877

Filed: April 9, 2001

Examiner:

For: SPATIAL AND SPECTRAL WAVEFRONT ANALYSIS
AND MEASUREMENT

Attorney Docket No.: U 013396-8

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

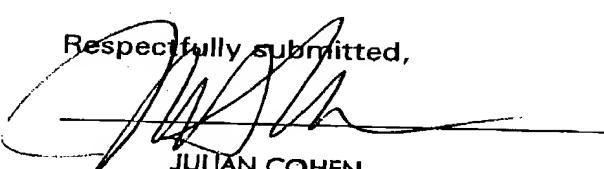
Sir:

FACSIMILE NO.: 703-305-4372
ATTN: Bernadette Queen

NO. OF PAGES: 4

As requested enclosed is the 1449 of December 10, 2001.

Respectfully submitted,



JULIAN COHEN
c/o LADAS & PARRY
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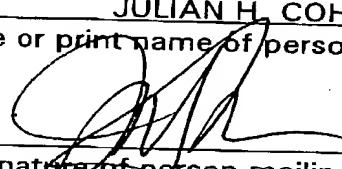
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Date December 16, 2001 Page 1 of 3

FORM PTO-1449 (Rev. 10-94)

ATTY DOCKET NO.

SERIAL NUMBER

1-4033596-8

09-826-435

LIST OF PATENTS AND PUBLICATIONS
FOR APPLICANT'S INFORMATION
STATEMENT

APPLICANT

Yoel ARIFI, et al

FILING DATE

April 9, 2001

GROUP PART UNIT

2877

U.S. PATENT DOCUMENTS

Examiner's Initials	DOCUMENT NO.	DATE	NAME	CLASS	SUB.	FILED
AB	5,969,855	Oct 1999	Ishiwata, et al	359	386	
AB	5,969,853	Oct 1999	Takaoka	359	370	
AC	5,936,253	Aug 1999	Nugoya	250	548	
AD	5,870,191	Feb 1999	Shirley, et al	343	356	
AE	5,814,815	Sep 1998	Matsumoto, et al	250	311	
AF	5,751,423	May 1998	Ishiwata, et al	359	387	
AG	5,649,372	Apr 1997	Hellmuth, et al	359	289	
AH	5,600,440	Feb 1997	Bendall	356	345	

FOREIGN PATENT DOCUMENTS

	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB.	TRANSLATION
AI	JP 92230247	4/1997	Japan			
AJ	JP 91159620	7/1997	Japan			
AK	JP 89049306	4/1996	Japan			

OTHER ART (Indicate value 10% or less on pages 1-2)

AI Philbin D W "General Methods for Generating Phase-Shifting Interferometry Algorithms" Applied Optics Vol. 36, 8098 (1997)
AM Pluta M "Stay-light Problem in Phase Contrast Microscope or Toward Highly Sensitive Phase Contrast Devices -A review" Optical engineering Vol. 32, 3196 (1993)

EXAMINER

DATE CONSIDERED

12/16/01

EXAMINER Initials reference considered whether or not citation is in conformance with AIA P-0000. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date December 4, 2001 Page 3 of 3

FORM PTO-1449 (04/01)

ATTY DOCKET NO.

SERIAL NUMBER

140155968

09 829,435

LIST OF PATENTS AND PUBLICATIONS
FOR APPLICANT'S INFORMATION
STATEMENT

APPLICANT
Yael ARIBI et al.

FILING DATE
April 9, 2001 GROUP ART UNIT
2977

U.S. PATENT DOCUMENTS

Examiner's Initials	DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
AC	5,159,474	Oct 1992	Franke, et al.	359	29	
AB	5,777,736	Jul 1998	Horton	356	346	
AC	4,653,921	Mar 1987	Kwon	356	353	
AD						
AI						

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DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANSLATION
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GB 2,315,700	2/1998	Great Britain			
AI					

OTHER ART (including Active 10's, Patentee Dies, Etc.)

AK
Golden J. J. "Wavefront Test - Analytical Aspects" Applied Optics, Vol. 16, 205 (1977)
AK
Bruning J.H. et al. "Digital Wavefront Measuring Interferometry for Testing Optical Surfaces and Lenses" Applied Optics, Vol. 15, 2693 (1976)

AK

AI

EXAMINER *S. W.* DATE CONSIDERED 11/16/03

EXAMINER Initial if reference considered whether or not citation is in conformance with MPEP
first. Draw line through citation if not in conformance and not considered. Include
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FORM PTO-1449 (Gib)

ATTY DOCKET NO.

SERIAL NUMBER

1-013596-8

09 829,435

LIST OF PATENTS AND PUBLICATIONS
FOR APPLICANT'S INFORMATION
STATEMENT

APPLICANT
Yoel ARIE Et al.

FILING DATE

April 9, 2001

GROUP ART UNIT

2877

U.S. PATENT DOCUMENTS

Examiner's
Initials

Initials

DOCUMENT NO.	DATE	NAME	CLASS	SUB.	FILING DATE
AA 5,171,303	Nov 1995	Al et al.	356	257	
AB 5,446,540	Aug 1996	Lin	356	345	
AC 5,235,587	Apr 1993	Bearden, et al.	369	106	
AD 4,407,569	Oct 1983	Piller, et al.	350	509	
AE 3,190,566	Feb 1980	Doyle	356	346	

FOREIGN PATENT DOCUMENTS

Examiner's
Initials

Initials

DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB.	TRANSLATION
AI JP 7261089	10/1995	Japan			
AG JP 7225341	8/1995	Japan			
AH JP 6126504	7/1994	Japan			

OTHER ART (including Author, Title, Patent, Pages, Etc.)

Examiner's
Initials

Initials

M Noda I. and Kawata S. "Separation of Phase and Absorption Images in Phase-contrast Microscopy", Journal of the Optical Society of America A, Vol. 9, 924 (1992).

AD Creath K. "Phase Measurement Interferometry Techniques", Progress in Optics XXVI, 348 (1988).

AK Givenskamp J.L. "Generalized Data Reduction for heterodyne Interferometry", Optical Engineering, Vol. 23, 357 (1984).

AE Morgan C.J. "Least Squares Estimation in Phase-Measurement Interferometry", Optics Letters, Vol. 7, 368 (1982).

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FORM PTO-1449 (Colb)		ATTY DOCKET NO. U-013396-8	SERIAL NUMBER 09/829,435
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT		APPLICANT Yoel ARIELI, et al.	
		FILING DATE April 9, 2001	GROUP ART UNIT 2877

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	AK	JP 8094936	4/1996	Japan			

OTHER ART (Including Author, Bills, Pertinent Pages, Etc.)

AL	Phillion D.W. "General Methods for Generating Phase-Shifting Interferometry Algorithms", Applied Optics, Vol. 36, 8098 (1997).
AM	Pluta M., "Stray-Light Problem in Phase Contrast Microscopy or Toward Highly Sensitive Phase Contrast Devices: A review", Optical engineering, Vol. 32, 3199 (1993).
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